

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/072,357	KILGORE, MICHAEL D.	
Examiner Maria Guerrero	Art Unit 2822	Page 1 of 1	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,132,244	07-1992	Roy	438/477
	C	US-5,851,892	12-1998	Lojek et al.	438/305
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	I	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Li et al. "Gate Oxide Damage Reduction and Antenna Yield Improvement Using Low temperature Preclean for Sub-0.25 microns Metallization", June 1999, IEEE, pages 134-136.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.